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Microbeam analysis - Analytical electron microscopy - Vocabulary

Contents

Page

Foreword iv

Introduction v

0 Scope 1

1 Abbreviated terms 1

2 Definitionsoftermsusedinthephysicalbasisof AEM 2

3 DefinitionsoftermsusedinAEMinstrumentation 5

4 Definitionsoftermsusedinspecimenpreparationof AEM 10

5 DefinitionsoftermsusedinAEMimageformationandprocessing 11

6 DefinitionsoftermsusedinAEMimageinterpretationandanalysis 13

7 Definitionsoftermsusedinthemeasurementandcalibrationof AEMimagemagnification and resolution 17

8 Definitionsoftermsusedinelectrondiffractionin AEM 18

Bibliography 21